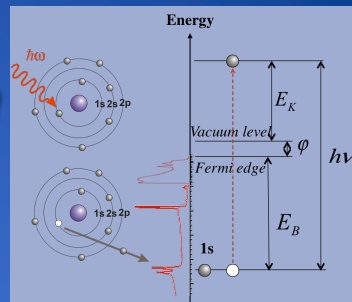
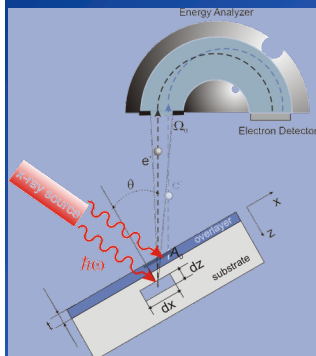


December 7 – 9, 2021 @ 9:00am-1:00pm
Birck Nanotechnology Center Rm1001 and 2001
Practical aspects of XPS:

from sample preparation
to spectra interpretation



Course Objectives:

- Learn basic physics principles and limitations of X-ray Photoelectron Spectroscopy (XPS) also know as ESCA (Electron Spectroscopy for Chemical Analysis)
- Learn approaches for qualitative and quantitative analysis of XPS data.
- Learn the types of problems that can be solved with XPS examples
- Perform advanced data analysis: coverage calculation, thin film thickness calculation, etc.

Course Description:

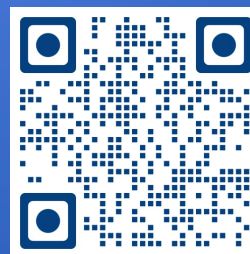
XPS is widely used to determine the chemical composition of a surface (element concentrations, chemical states, lateral and depth distributions, etc.) Nowadays XPS has become a standard technique for the characterization of solid surfaces. The course will teach how and what information can be provided by XPS.

Audience:

The lecture is orientated at a general audience. Scientists, engineers, students and technicians who would like a detailed understanding for the use of XPS/ESCA for surface analysis. ***Ideally, every group involved in Surface Characterization should have at least one designated student familiar with XPS***

Total Cost: \$250 (lunch will be provided)

Registration at: <https://forms.gle/B7xjCHWADG9yVmTk6>



Instructor:

Dmitry Zemlyanov,



PhD, Senior Surface Science Application Scientist,
Birck Nanotechnology Center, Purdue University

